

Search Notes

Application/Control No.

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Examiner

Hanh V. Tran

Applicant(s)/Patent under
Reexamination

DEISS ET AL.

Art Unit

3637

SEARCHED

Class	Subclass	Date	Examiner
312	334.4 311	2/2/2006	HVT
	350 351		
134	137 58D		
	200 201	2/2/2006	
211	41.8 41.9	2/4/2006	
	175 181.1		
211	207 208	2/4/2006	HVT

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
East text search using various key words	2/2/2006	HVT